

Deutsche Akkreditierungsstelle

Annex to the Partial Accreditation Certificate D-K-15118-01-01 according to DIN EN ISO/IEC 17025:2018

Valid from: 10.07.2023

Date of issue: 10.07.2023

This annex is a part of the accreditation certificate D-K-15118-01-00.

Holder of partial accreditation certificate:

Kessler QMP GmbH
Nisterberger Weg 16, 57520 Friedewald

The calibration laboratory meets the requirements of DIN EN ISO/IEC 17025:2018 to carry out the conformity assessment activities listed in this annex. The calibration laboratory meets additional legal and normative requirements, if applicable, including those in relevant sectoral schemes, provided that these are explicitly confirmed below.

The management system requirements of DIN EN ISO/IEC 17025 are written in the language relevant to the operations of calibration laboratories and confirm generally with the principles of DIN EN ISO 9001.

Calibrations in the fields:

Dimensional quantities

Length

- **Length gauges**
- **Diameter** ^{b)}
- **Form error**
- **Length measuring instruments** ^{b)}
- **Length measuring devices** ^{a)}
- **Flatness** ^{a)}
- **Straightness**
- **Line scales, distances**
- **Thread** ^{b)}

This certificate annex is only valid together with the written accreditation certificate and reflects the status as indicated by the date of issue. The current status of any given scope of accreditation can be found in the directory of accredited bodies maintained by Deutsche Akkreditierungsstelle GmbH at <https://www.dakks.de>.

Abbreviations used: see last page

This document is a translation. The definitive version is the original German annex to the accreditation certificate.

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- **Gear quantities**
- Coordinate measuring technology**
 - **Application coordinate measuring machines**
 - **Coordinate measuring machines^{c)}**
- Angle**
 - **Angle gauges**
 - **Inclination measuring instruments**

Electrical quantities

DC and low frequency quantities

- **DC voltage^{b)}**
- **AC voltage^{b)}**
- **DC current^{b)}**
- **AC current^{b)}**
- **DC resistance^{b)}**
- **Electric power^{b)}**

Time and frequency

- **Frequency**
- **Time interval**

High frequency and radiation quantities

High frequency quantities

- **Oscilloscope quantities^{b)}**
- **Rise time^{b)}**
- **Band width^{b)}**

^{a)} also on-site-calibration

^{b)} also calibration in the mobile laboratory

^{c)} only on-site-calibration

Within the measurands/calibration items marked with *, the calibration laboratory is permitted, without being required to inform and obtain prior approval from DAkkS, to use calibration standards or equivalent calibration procedures listed here with different issue dates.

The calibration laboratory maintains a current list of all calibration standards / equivalent calibration procedures within the flexible scope of accreditation.

¹ Unless otherwise specified, the unit of a variable corresponds to the unit of the measuring range.

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Permanent Laboratory

Calibration and Measurement Capabilities (CMC)				
Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Length Gauge blocks * made of steel according to DIN EN ISO 3650:1999	0.5 mm to 100 mm featuring the nominal values of the steel standards	VDI/VDE/DGQ 2618 part 3.1:2004 Measurement of the deviation of the central length l_c from the nominal value l_n by comparison measurement Measurement of the deviations f_o and f_u from the central length by 5 points comparison measurement For the smallest measurement uncertainties, the wringability and the wringing characteristics of both measuring surfaces must be checked using an appropriate optical flat	For the central length: $0.08 \mu\text{m} + 0.8 \cdot 10^{-6} \cdot l$ For the deviations f_o and f_u from the central length: $0.05 \mu\text{m}$	l = gauge block length
Gauge blocks * made of ceramics according to DIN EN ISO 3650:1999			For the central length: $0.1 \mu\text{m} + 1.1 \cdot 10^{-6} \cdot l$ For the deviations f_o and f_u from the central length: $0.07 \mu\text{m}$	
Gauge blocks * made of tungsten carbite according to DIN EN ISO 3650:1999			For the central length: $0.1 \mu\text{m} + 3.3 \cdot 10^{-6} \cdot l$ For the deviations f_o and f_u from the central length: $0.07 \mu\text{m}$	
Setting plug gauges * Diameter	1 mm to 500 mm	VDI/VDE/DGQ 2618 part 4.1:2006, option 1, option 2 Option 3, option 4	$0.4 \mu\text{m} + 4 \cdot 10^{-6} \cdot d$	d = measured diameter
Roundness deviation	to 40 μm		$0.8 \mu\text{m} + 3 \cdot 10^{-6} \cdot d$	
Straightness deviation	to 40 μm	VDI/VDE/DGQ 2618 part 4.1:2006	$0.3 \mu\text{m} + 2.5 \cdot 10^{-2} \cdot RONt$	
Parallelism deviation	to 40 μm		$0.4 \mu\text{m} + 2.5 \cdot 10^{-2} \cdot STRt$	
Setting ring gauges * Diameter	2 mm to 200 mm		$0.7 \mu\text{m} + 2.5 \cdot 10^{-2} \cdot PARt$	
Roundness deviation	to 40 μm	VDI/VDE/DGQ 2618 part 4.1:2006	$0.6 \mu\text{m} + 3 \cdot 10^{-6} \cdot d$	d = measured diameter
Straightness deviation	to 40 μm		$0.8 \mu\text{m} + 3 \cdot 10^{-6} \cdot d$	
Parallelism deviation	to 40 μm		$0.3 \mu\text{m} + 2.5 \cdot 10^{-2} \cdot RONt$	
Roundness deviation	to 40 μm	TK 40:2020-01	$0.4 \mu\text{m} + 2.5 \cdot 10^{-2} \cdot STRt$	
Straightness deviation	to 40 μm		$0.7 \mu\text{m} + 2.5 \cdot 10^{-2} \cdot PARt$	
Parallelism deviation	to 40 μm		$0.3 \mu\text{m} + 2.5 \cdot 10^{-2} \cdot RONt$	
Measuring pins / Pins for screw threads *	1 mm to 50 mm 0.17 mm to 50 mm	VDI/VDE/DGQ 2618 part 4.2:2007, option 1, option 2 Option 3	$0.4 \mu\text{m} + 2.5 \cdot 10^{-2} \cdot STRt$	
Diametererr			$0.6 \mu\text{m}$	
Roundness deviation	to 40 μm	VDI/VDE/DGQ 2618 part 4.1:2006	$0.8 \mu\text{m}$	
Straightness deviation	to 40 μm		$0.3 \mu\text{m} + 2.5 \cdot 10^{-2} \cdot RONt$	

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Calibration and Measurement Capabilities (CMC)				
Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Taper gauges * Taper plug gauges and Taper ring gauges Diameter	1 mm to 200 mm	VDI/VDE/DGQ 2618 part 4.12:2007, option 1 and 2	The uncertainty of measurement is determined with a uncertainty measurement balance sheet on the basic of the guideline VDI/VDE 2617 part 11:2011. The uncertainty of measurement is specified with a coverage probability of approximately 95 % (coverage factor $k = 2$) Exemplary of Uncertainty of measurement for a measuring problem: Taper plug gauge with a gap of 61 mm to the measuring high and a gap of 2 mm to the last measuring plane at the evaluation flat: $U = 0.42 \mu\text{m}$	
Penetration radius			(90 mm/l)''	Statement of l in mm
Angular deviation	to 5'		0.5 μm	
Roundness deviation	to 40 μm		0.5 μm	
Straightness deviation	to 40 μm			
Gap gauges *	5 mm to 200 mm	VDI/VDE/DGQ 2618 part 4.7:2005	$3 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	l = measured length
Straight edges * Flatness deviation	to 1000 mm	VDI/VDE/DGQ 2618 part 5.1:2013	$1.1 \mu\text{m} + 1.6 \cdot 10^{-6} \cdot l$	
Parallelism deviation			$2.2 \mu\text{m} + 3.2 \cdot 10^{-6} \cdot l$	
Knife straight edges *	to 1000 mm	VDI/VDE/DGQ 2618 part 5.2:2013	$1.1 \mu\text{m} + 1.6 \cdot 10^{-6} \cdot l$	
Surface plates * Flatness deviation	to 50 μm	VDI/VDE/DGQ 2618 part 6.2:2014 to 8 m edge length	$1.1 \mu\text{m} + 2.7 \cdot 10^{-6} \cdot l$	l = measured length with inclination measuring instruments
Steel squares * Flatness deviation	to 1000 mm	VDI/VDE/DGQ/DKD 2618 part 7.1:2019	$1.1 \mu\text{m} + 1.6 \cdot 10^{-6} \cdot l$	
Angular deviation			$3.1 \mu\text{m} + 5 \cdot 10^{-6} \cdot l$	
Centring angles Flatness deviation	to 1000 mm	TK 90:2021-09	$1.1 \mu\text{m} + 1.6 \cdot 10^{-6} \cdot l$	l = measured length
Angular deviation			$3.1 \mu\text{m} + 5 \cdot 10^{-6} \cdot l$	

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Protractors * Flatness deviation	0° to 360°	VDI/VDE/DGQ 2618 part 7.2:2008	5 µm	
Parallelism deviation			5 µm	
Angle * Scale interval 5'			4'	
Scale interval 1°			24'	
Calipers for external, internal and depth dimensions *	0 mm to 300 mm	VDI/VDE/DGQ 2618 part 9.1:2006	30 µm + 30 · 10 ⁻⁶ · l	<i>l</i> = final value of the measuring range
	> 300 mm to 1500 mm		50 µm + 30 · 10 ⁻⁶ · l	
	> 1500 mm to 3000 mm		70 µm + 30 · 10 ⁻⁶ · l	
Depth calipers *	0 mm to 300 mm	VDI/VDE/DGQ 2618 part 9.2:2006	30 µm + 30 · 10 ⁻⁶ · l	
	> 300 mm to 1500 mm		50 µm + 30 · 10 ⁻⁶ · l	
Height calipers * with analogue display	0 mm to 600 mm	VDI/VDE/DGQ 2618 part 9.3:2006	30 µm + 30 · 10 ⁻⁶ · l	
with digital display			20 µm + 30 · 10 ⁻⁶ · l	
Micrometers *	0 mm to 100 mm	VDI/VDE/DGQ 2618 part 10.1:2001	3 µm + 10 · 10 ⁻⁶ · l	
	> 100 mm to 500 mm		4 µm + 10 · 10 ⁻⁶ · l	
Micrometers	> 500 mm to 1000 mm	TK 2:2020-02	5 µm + 10 · 10 ⁻⁶ · l	
	> 1000 mm to 1500 mm		6 µm + 10 · 10 ⁻⁶ · l	
Reference gauges for micrometers *	25 mm to 500 mm	VDI/VDE/DGQ 2618 part 4.4:2009	2 µm + 5 · 10 ⁻⁶ · l	<i>l</i> = measured length
	> 500 mm to 1500 mm		3 µm + 5 · 10 ⁻⁶ · l	
Micrometers with interchangeable inserts *	0 mm to 100 mm	VDI/VDE/DGQ 2618 part 10.2:2010	3 µm + 10 · 10 ⁻⁶ · l	
	> 100 mm to 300 mm		5 µm + 10 · 10 ⁻⁶ · l	
Micrometers with dial indicator *	0 mm to 100 mm	VDI/VDE/DGQ 2618 part 10.3:2002	3 µm + 10 · 10 ⁻⁶ · l	
Micrometers heads *	0 mm to 50 mm	VDI/VDE/DGQ 2618 part 10.4:2008	3 µm + 10 · 10 ⁻⁶ · l	
Depth micrometers *	0 mm to 100 mm	VDI/VDE/DGQ 2618 part 10.5:2010	3 µm + 10 · 10 ⁻⁶ · l	
	> 100 mm to 500 mm		4 µm + 10 · 10 ⁻⁶ · l	
Internal micrometers with two-point contact *	25 mm to 100 mm	VDI/VDE/DGQ 2618 part 10.7:2010	3 µm + 10 · 10 ⁻⁶ · l	
	> 100 mm to 500 mm		4 µm + 10 · 10 ⁻⁶ · l	
	> 500 mm to 1000 mm		5 µm + 10 · 10 ⁻⁶ · l	
	> 1000 mm to 1500 mm		6 µm + 10 · 10 ⁻⁶ · l	
Extensions for internal micrometers with two-point contact *	25 mm to 500 mm	VDI/VDE/DGQ 2618 part 10.7:2010	2 µm + 5 · 10 ⁻⁶ · l	
	> 500 mm to 1500 mm		3.5 µm + 5 · 10 ⁻⁶ · l	

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Internal micrometers with three-point contact *	3 mm to 200 mm	VDI/VDE/DGQ 2618 part 10.8:2002	$4 \mu\text{m} + 10 \cdot 10^{-6} \cdot d$	$d = \text{measured diameter}$
Internal measuring instruments	3 mm to 200 mm	TK 57:2021-02	$2 \mu\text{m} + 10 \cdot 10^{-6} \cdot d$	$d = \text{measured diameter}$
Dial gauges * Scale interval $> 1 \mu\text{m}$	to 100 mm	VDI/VDE/DGQ/DKD 2618 part 11.1:2021	$3 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	$l = \text{measured length}$
Scale interval $\leq 1 \mu\text{m}$			$2 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	
Dial indicators *	to 3 mm	VDI/VDE/DGQ 2618 part 11.2:2002	1.1 μm	
Lever gauges *	to 1.6 mm	VDI/VDE/DGQ 2618 part 11.3:2002	1.2 μm	
Dial gauges * with digital display	to 100 mm	VDI/VDE/DGQ/DKD 2618 part 11.4:2020	$3 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	
Lever gauges (quicktests) for external measurements *	0 mm to 100 mm	VDI/VDE/DGQ 2618 part 12.1:2005	6 μm	
Thickness gauges * Scale interval 1 μm	0 mm to 30 mm	VDI/VDE/DGQ 2618 part 12.1:2005	$1.3 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	$l = \text{measured length}$
Scale interval 10 μm			$6 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	
Lever gauges (quicktests) for internal measurements *	2.5 mm to 500 mm	VDI/VDE/DGQ 2618 part 13.1:2005	6 μm	
Bore gauges with two-point contact * Form I – III	1 mm to 800 mm	VDI/VDE/DGQ 2618 part 13.2:2005	1.8 μm	Measuring length up to 3 mm
Electrical probe and measuring device *	0 mm to 10 mm	VDI/VDE/DGQ 2618 part 14.1:2010	1.4 μm	
Feeler gauges	10 μm to 2 mm	TK 19:2021-02	1 μm	
Measuring tape, Circumference tape measure	0 m to 100 m	TK 85:2020-01	$56 \mu\text{m} + 46 \cdot 10^{-6} \cdot l$	$l = \text{measured length}$
Rules	0 m to 5 m	TK 85:2020-01	$56 \mu\text{m} + 46 \cdot 10^{-6} \cdot l$	Graduated metal rules, reference- and plotting scale, rules, folding rules
Diameter tape measure	0 m to 10 m	TK 85:2020-01	$56 \mu\text{m} + 46 \cdot 10^{-6} \cdot l$	
Setting dimension for height gauges	to 20 mm	TK 89:2020-01	0.5 μm	

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Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Height gauges *	0 mm to 1000 mm	VDI/VDE/DGQ 2618 part 16.1:2009	1.0 $\mu\text{m} + 1.4 \cdot 10^{-6} \cdot l$	till 1000 mm lead length
Deviation from straightness and perpendicularity	to 40 μm		3 μm	l = measured length
Horizontal length measuring device *	0 mm to 5000 mm	VDI/VDE/DGQ 2618 part 17.1:2015	0.12 $\mu\text{m} + 0.07 \cdot 10^{-6} \cdot l$	with laser interferometer
	0 mm to 200 mm		0.12 $\mu\text{m} + 0.6 \cdot 10^{-6} \cdot l$	with gauge blocks
Thread gauges * single-start cylindrical external and internal threads with straight flanks, symmetrical profile and nominal thread angle 55° to 60°				
External thread with nominal lead 0.25 mm to 5.5 mm Simple pitch diameter	Nominal diameter: 2 mm to 200 mm	VDI/VDE/DGQ 2618 part 4.8:2006 (option 1) Three wire procedure (vertical to thread axis)	2.8 $\mu\text{m} + 10 \cdot 10^{-6} \cdot d$	d = pitch diameter
Internal thread with nominal lead 0.7 mm to 6.0 mm Simple pitch diameter	Nominal diameter: 4 mm to 200 mm	VDI/VDE/DGQ 2618 part 4.9:2006 (option 1) Two ball procedure (vertical to thread axis)	2.8 $\mu\text{m} + 10 \cdot 10^{-6} \cdot d$	d = Pitch diameter
Angle gauges 90 °	Leg length 40 mm to 1000 mm	TK 16:2021-05 pointwise measurement	2.4 μm	Angle auges of hard stone according to DIN 875-2:2008
Inclination measuring instruments elektronic and mechanical	± 20 mm/m	TK 56:2021-05	2.4 $\mu\text{m} + 10 \cdot 10^{-6} \cdot \alpha$	α = Nominal angle
	± 50 mm/m		21 $\mu\text{m}/\text{m}$	
	2.866° to 45°		0.01°	
	± 90°		2.3 $\mu\text{m}/\text{m}$	
	Zero point deviation		1.5 $\mu\text{m}/\text{m}$	
Caliper for trailer artifice	to 60 mm	TK 84:2021-08	2 μm	
Caliper for trailer artifice	to 120 mm	TK 83:2021-08	8 μm	
Layer thickness gauges	20 mm	TK 91:2021-07	0.7 $\mu\text{m} + 180 \cdot 10^{-6} \cdot l$	l = measured length
Calibration foil	20 mm	TK 70:2021-07	0.8 $\mu\text{m} + 130 \cdot 10^{-6} \cdot l$	
Micrometers according to DIN 863-3 form D10	0 mm to 100 mm	TK 2:2021-02	5 $\mu\text{m} + 10 \cdot 10^{-6} \cdot d$	d = measured diameter

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Calibration and Measurement Capabilities (CMC)				
Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Gear quantities Profile deviation *		VDI/VDE 2612-1:2018 Substitution measuring with 3D coordinate measuring machines Correction of F_a and f_{Ha} by comparison against gear measurement standard with $d_b = 29.88 \text{ mm}$ $L_a = 4 \text{ mm}$	1.6 μm 0.6 μm 1.4 μm	Internal and external gears Symbols according to: ISO 1328-1:2013
F_a f_{fa} f_{Ha}	10 mm $\leq d_b \leq$ 55 mm $L_a \leq$ 4 mm	$L_a = 4 \text{ mm}$ or rather with $d_b = 122.192 \text{ mm}$ $L_a = 24 \text{ mm}$	1.6 μm 0.6 μm 1.4 μm	
F_a f_{fa} f_{Ha}	10 mm $\leq d_b \leq$ 150 mm $L_a \leq$ 24 mm	VDI/VDE 2612-1:2018 Measurement with 3D coordinate measuring machines without correction; traceability proved by involute measurement standard with $d_b = 29.88 \text{ mm}$ $L_a = 4 \text{ mm}$ or rather with $d_b = 122.192 \text{ mm}$ $L_a = 24 \text{ mm}$	2.7 μm 1.0 μm 1.7 μm	
F_a f_{fa} f_{Ha}	10 mm $\leq d_b \leq$ 500 mm $L_a \leq$ 50 mm	VDI/VDE 2612-1:2018 Measurement with 3D coordinate measuring machines without correction; traceability proved by involute measurement standard with $d_b = 29.88 \text{ mm}$ $L_a = 4 \text{ mm}$ or rather with $d_b = 122.192 \text{ mm}$ $L_a = 24 \text{ mm}$	3.4 μm 1.0 μm 3.3 μm	

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Helix deviation *				
F_β	10 mm $\leq d \leq$ 55 mm	VDI/VDE 2612-1:2018 Substitution measuring with 3D coordinate measuring machines	1.5 µm	Internal and external gears
f_{β}	$L_\beta \leq$ 40 mm	Correction of F_β and $f_{H\beta}$ by comparison against gear measurement standard with $d = 34.5$ mm	0.7 µm	Symbols according to: ISO 1328-1:2013
$f_{H\beta}$	$0^\circ < \beta \leq 5^\circ$	$L_\beta = 30$ mm $\beta = 0^\circ$ or rather with $d = 104$ mm $L_\beta = 64$ mm $\beta = 0^\circ$ $\beta = 15^\circ r+l$ $\beta = 30^\circ r+l$	1.3 µm	
F_β	100 mm $\leq d \leq$ 150 mm	VDI/VDE 2612-1:2018	1.5 µm	
f_{β}	$L_\beta \leq$ 64 mm	Measurement with 3D coordinate measuring machines without correction; traceability proved by helix measurement standard with $d = 34.5$ mm	0.7 µm	
$f_{H\beta}$	$0^\circ < \beta \leq 5^\circ$	$L_\beta = 30$ mm $\beta = 0^\circ$ or rather with $d = 104$ mm $L_\beta = 64$ mm $\beta = 0^\circ$ $\beta = 15^\circ r+l$ $\beta = 30^\circ r+l$	1.3 µm	
F_β	100 mm $\leq d \leq$ 150 mm	VDI/VDE 2612-1:2018	1.6 mm	
f_{β}	$L_\beta \leq$ 64 mm	Measurement with 3D coordinate measuring machines without correction; traceability proved by helix measurement standard with $d = 34.5$ mm	0.7 mm	
$f_{H\beta}$	$10^\circ < \beta \leq 20^\circ$	$L_\beta = 30$ mm $\beta = 0^\circ$ or rather with $d = 104$ mm $L_\beta = 64$ mm $\beta = 0^\circ$ $\beta = 15^\circ r+l$ $\beta = 30^\circ r+l$	1.4 mm	
F_β	100 mm $\leq d \leq$ 150 mm	VDI/VDE 2612-1:2018	1.9 µm	
f_{β}	$L_\beta \leq$ 40 mm	Measurement with 3D coordinate measuring machines without correction; traceability proved by helix measurement standard with $d = 34.5$ mm	0.7 µm	
$f_{H\beta}$	$25^\circ < \beta \leq 35^\circ$	$L_\beta = 64$ mm $\beta = 0^\circ$ $\beta = 15^\circ r+l$ $\beta = 30^\circ r+l$	1.7 µm	
F_β	10 mm $\leq d \leq$ 150 mm	VDI/VDE 2612-1:2018	2.8 µm	
f_{β}	$L_\beta \leq$ 40 mm	Measurement with 3D coordinate measuring machines without correction; traceability proved by helix measurement standard with $d = 34.5$ mm	1.0 µm	
$f_{H\beta}$	$0^\circ < \beta \leq 10^\circ$	$L_\beta = 30$ mm $\beta = 0^\circ$ or rather with $d = 104$ mm $L_\beta = 64$ mm $\beta = 0^\circ$ $\beta = 15^\circ r+l$ $\beta = 30^\circ r+l$	2.6 µm	
F_β	100 mm $\leq d \leq$ 150 mm	VDI/VDE 2612-1:2018	2.8 µm	
f_{β}	$L_\beta \leq$ 64 mm	Measurement with 3D coordinate measuring machines without correction; traceability proved by helix measurement standard with $d = 34.5$ mm	1.0 µm	
$f_{H\beta}$	$5^\circ < \beta \leq 10^\circ$	$L_\beta = 30$ mm $\beta = 0^\circ$ or rather with $d = 104$ mm $L_\beta = 64$ mm $\beta = 0^\circ$ $\beta = 15^\circ r+l$ $\beta = 30^\circ r+l$	2.6 µm	
F_β	100 mm $\leq d \leq$ 150 mm	VDI/VDE 2612-1:2018	2.8 µm	
f_{β}	$L_\beta \leq$ 64 mm	Measurement with 3D coordinate measuring machines without correction; traceability proved by helix measurement standard with $d = 34.5$ mm	1.0 µm	
$f_{H\beta}$	$20^\circ < \beta \leq 25^\circ$	$L_\beta = 30$ mm $\beta = 0^\circ$ or rather with $d = 104$ mm $L_\beta = 64$ mm $\beta = 0^\circ$ $\beta = 15^\circ r+l$ $\beta = 30^\circ r+l$	2.6 µm	
F_β	100 mm $\leq d \leq$ 150 mm	VDI/VDE 2612-1:2018	3.6 µm	
f_{β}	$L_\beta \leq$ 64 mm	Measurement with 3D coordinate measuring machines without correction; traceability proved by helix measurement standard with $d = 34.5$ mm	1.0 µm	
$f_{H\beta}$	$35^\circ < \beta \leq 45^\circ$	$L_\beta = 64$ mm $\beta = 0^\circ$ $\beta = 15^\circ r+l$ $\beta = 30^\circ r+l$	3.4 µm	
F_β	10 mm $\leq d \leq$ 500 mm	VDI/VDE 2612-1:2018	3.4 µm	
f_{β}	$L_\beta \leq$ 200 mm	Measurement with 3D coordinate measuring machines without correction; traceability proved by helix measurement standard with $d = 34.5$ mm	1.0 µm	
$f_{H\beta}$	$\beta = 0^\circ$	$L_\beta = 30$ mm $\beta = 0^\circ$ or rather with $d = 104$ mm $L_\beta = 64$ mm $\beta = 0^\circ$ $\beta = 15^\circ r+l$ $\beta = 30^\circ r+l$	3.2 µm	
F_β	10 mm $\leq d \leq$ 500 mm	VDI/VDE 2612-1:2018	3.9 µm	
f_{β}	$L_\beta \leq$ 200 mm	Measurement with 3D coordinate measuring machines without correction; traceability proved by helix measurement standard with $d = 34.5$ mm	1.0 µm	
$f_{H\beta}$	$0^\circ < \beta \leq 35^\circ$	$L_\beta = 30$ mm $\beta = 0^\circ$ or rather with $d = 104$ mm $L_\beta = 64$ mm $\beta = 0^\circ$ $\beta = 15^\circ r+l$ $\beta = 30^\circ r+l$	3.7 µm	
F_β	10 mm $\leq d \leq$ 500 mm	VDI/VDE 2612-1:2018	4.3 µm	
f_{β}	$L_\beta \leq$ 200 mm	Measurement with 3D coordinate measuring machines without correction; traceability proved by helix measurement standard with $d = 34.5$ mm	1.0 µm	
$f_{H\beta}$	$35^\circ < \beta \leq 45^\circ$	$L_\beta = 64$ mm $\beta = 0^\circ$ $\beta = 15^\circ r+l$ $\beta = 30^\circ r+l$	4.2 µm	

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Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Pitch deviation * F_p f_p F_x	10 mm $\leq d \leq$ 500 mm $\beta =$ 0° $m_n >$ 0.5 mm	VDI/VDE 2613:2003 Measurement according to „Rosette method“ with 3D coordinate measuring machines	1.0 µm 0.9 µm 1.1 µm	Internal and external gears Symbols according to: ISO 1328-1:2013
F_p f_p F_x	10 mm $\leq d \leq$ 500 mm $\beta =$ 0° $m_n >$ 0.5 mm	VDI/VDE 2613:2003 Measurement with 3D coordinate measuring machines without correction; traceability proved by pitch measurement standard with $d = 67$ mm $m_n = 1$ mm	5.1 µm 2.2 µm 5.2 µm	
Dimension over balls * M_{dK}	10 mm $\leq M_{dK} \leq$ 150 mm $\beta =$ 0° $m_n >$ 0.5 mm	DIN 21773:2014 Measurement of M_{dK} on length comparator compared to traceable setting standard i	$1.4 \mu\text{m} + 11 \cdot 10^{-6} \cdot l$	Internal and external gears Symbols according to: ISO 1328-1:2013

¹ Unless otherwise specified, the unit of a variable corresponds to the unit of the measuring range.

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Annex to the Partial Accreditation Certificate D-K-15118-01-01

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Calibration and Measurement Capabilities (CMC)				
Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Coordinate measuring technology Prismatic, tapered and ball-shaped workpieces	Coordinate measuring machine with calibrated measuring volume of: X = 1200 mm Y = 1000 mm Z = 700 mm	TK 55:2020-02 Tactile measurements with single point probing with a coordinate measuring machine and determination of regular geometries through geometrical parameters (single-points, straight lines, planes, circles, balls, cylinders, tapers, toroid's) using the evaluation software of the coordinate measuring machine. Single-point measuring is carried out with fixed, predefined measuring force. Single point measurements in the form of „Self-centering measurements“ are not used within the accreditation. For ensuring metrological traceability calibration of a similar standard will be realized. Beyond that following limitations should be considered: <ul style="list-style-type: none"> - Measuring points have to be evenly distributed over the form element; - The calibration values can be determined in a multilayer method by averaging in order to reduce the measurement uncertainty. 	The uncertainty of measurement is determined with a uncertainty measurement balance sheet on the basis of the guideline VDI/VDE 2617 part 11:2011. The uncertainty of measurement for specific feedings is specified with a coverage probability of approximately 95 % (coverage factor $k = 2$) Exemplary measurement uncertainty for a described measuring tasks: Gauge block with a nominal value of 1000 mm, determined is the expanded uncertainty of the inspection feature „Distance“: $U = 4.8 \mu\text{m}$	For general measuring tasks the measuring uncertainty could be significant differently from the exemplary specified.

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Calibration and Measurement Capabilities (CMC)				
Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Radius gauges	1 mm to 2500 mm	TK 86:2020-01	The uncertainty of measurement is determined with a uncertainty measurement balance sheet on the basic of the guideline VDI/VDE 2617 part 11:2011. The uncertainty of measurement is specified with a coverage probability of approximately 95 % (coverage factor $k = 2$) Uncertainty of measurement for a measuring problem: Radius with nominal value of 4 mm and an arc of 70°: $U = 10 \mu\text{m}$	
Calibration of control geometries of test and setting gauges with utilities		TK 88:2020-11		
			$38 \mu\text{m} + 26 \cdot 10^{-6} \cdot l$	Calipers, height gauges
			$4.9 \mu\text{m} + 2 \cdot 10^{-6} \cdot l$	Micrometers
			$0.2 \mu\text{m} + 4 \cdot 10^{-6} \cdot l$	Horizontal and vertical length measuring device
			$2.5 \mu\text{m} + 2.7 \cdot 10^{-6} \cdot l$	Bore gauges
			0.08°	Universal angle meter, protractors
DC and low frequency quantities				
DC voltage Measuring instruments	1 mV to < 330 mV 0.33 V to < 3.3 V 3.3 V to < 33 V 33 V to < 330 V 330 V to < 1000 V		$2.0 \mu\text{V} + 35 \cdot 10^{-6} \cdot U$ $3.0 \mu\text{V} + 16 \cdot 10^{-6} \cdot U$ $24 \mu\text{V} + 18 \cdot 10^{-6} \cdot U$ $0.2 \text{mV} + 24 \cdot 10^{-6} \cdot U$ $1.7 \text{mV} + 24 \cdot 10^{-6} \cdot U$	$U = \text{measured value}$
DC voltage Sources	10 mV to 120 mV > 0.12 V to 1.2 V > 1.2 V to 12 V > 12 V to 120 V > 120 V to 1050 V		$2.0 \mu\text{V} + 12 \cdot 10^{-6} \cdot U$ $2.0 \mu\text{V} + 10 \cdot 10^{-6} \cdot U$ $2.5 \mu\text{V} + 10 \cdot 10^{-6} \cdot U$ $35 \mu\text{V} + 14 \cdot 10^{-6} \cdot U$ $0.1 \text{mV} + 22 \cdot 10^{-6} \cdot U$	

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Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
AC voltage Measuring instruments	1 mV to < 33 mV	10 Hz to 45 Hz > 45 Hz to 10 kHz > 10 kHz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz > 100 kHz to 500 kHz	8 µV + 1.0 · 10 ⁻³ · U 8 µV + 0.2 · 10 ⁻³ · U 8 µV + 0.25 · 10 ⁻³ · U 8 µV + 1.3 · 10 ⁻³ · U 15 µV + 4.2 · 10 ⁻³ · U 60 µV + 10 · 10 ⁻³ · U	$U = \text{measured value}$
	33 mV to < 330 mV	10 Hz to 45 Hz > 45 Hz to 10 kHz > 10 kHz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz > 100 kHz to 500 kHz	10 µV + 0.4 · 10 ⁻³ · U 10 µV + 0.2 · 10 ⁻³ · U 10 µV + 0.2 · 10 ⁻³ · U 10 µV + 0.43 · 10 ⁻³ · U 40 µV + 0.95 · 10 ⁻³ · U 85 µV + 2.5 · 10 ⁻³ · U	
	0.33 V to < 3,3 V	10 Hz to 45 Hz > 45 Hz to 10 kHz > 10 kHz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz > 100 kHz to 500 kHz	60 µV + 0.4 · 10 ⁻³ · U 75 µV + 0.2 · 10 ⁻³ · U 75 µV + 0.24 · 10 ⁻³ · U 60 µV + 0.35 · 10 ⁻³ · U 0.15 mV + 0.85 · 10 ⁻³ · U 0.7 mV + 3 · 10 ⁻³ · U	
	3.3 V to < 33 V	10 Hz to 45 Hz > 45 Hz to 10 kHz > 10 kHz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz	0.75 mV + 0.38 · 10 ⁻³ · U 0.7 mV + 0.2 · 10 ⁻³ · U 0.7 mV + 0.29 · 10 ⁻³ · U 0.7 mV + 0.42 · 10 ⁻³ · U 1.9 mV + 1.1 · 10 ⁻³ · U	
	33 V to < 330 V	10 Hz to 45 Hz > 45 Hz to 10 kHz > 10 kHz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz	2.4 mV + 0.24 · 10 ⁻³ · U 7 mV + 0.25 · 10 ⁻³ · U 7 mV + 0.31 · 10 ⁻³ · U 7 mV + 0.37 · 10 ⁻³ · U 58 mV + 2.4 · 10 ⁻³ · U	
	330 V to < 1000 V	45 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz	13 mV + 0.35 · 10 ⁻³ · U 13 mV + 0.30 · 10 ⁻³ · U 13 mV + 0.35 · 10 ⁻³ · U	
AC voltage Sources	10 mV to 120 mV	10 Hz to 40 Hz > 40 Hz to 1 kHz > 1 kHz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz > 100 kHz to 300 kHz	25 µV + 0.11 · 10 ⁻³ · U 20 µV + 0.11 · 10 ⁻³ · U 20 µV + 0.19 · 10 ⁻³ · U 20 µV + 0.38 · 10 ⁻³ · U 20 µV + 1 · 10 ⁻³ · U 20 µV + 4.2 · 10 ⁻³ · U	
	> 0.12 V to 1.2 V	10 Hz to 40 Hz > 40 Hz to 1 kHz > 1 kHz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz > 100 kHz to 300 kHz > 300 kHz to 1 MHz	60 µV + 0.10 · 10 ⁻³ · U 40 µV + 0.10 · 10 ⁻³ · U 40 µV + 0.18 · 10 ⁻³ · U 40 µV + 0.37 · 10 ⁻³ · U 40 µV + 1.15 · 10 ⁻³ · U 0.15 mV + 4 · 10 ⁻³ · U 0.15 mV + 17 · 10 ⁻³ · U	

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Calibration and Measurement Capabilities (CMC)						
Measurement quantity / Calibration item	Range		Measurement conditions / procedure		Expanded uncertainty of measurement ¹	Remarks
AC voltage Sources	> 1.2 V to 12 V	10 Hz to 40 Hz	to 40 Hz	10 Hz to 40 Hz	0.6 mV + 90 · 10 ⁻⁶ · U	<i>U</i> = measured value
		> 40 Hz to 1 kHz	to 1 kHz	> 40 Hz to 1 kHz	0.3 mV + 88 · 10 ⁻⁶ · U	
		> 1 kHz to 20 kHz	to 20 kHz	> 1 kHz to 20 kHz	0.3 mV + 0.17 · 10 ⁻³ · U	
		> 20 kHz to 50 kHz	to 50 kHz	> 20 kHz to 50 kHz	0.3 mV + 0.36 · 10 ⁻³ · U	
		> 50 kHz to 100 kHz	to 100 kHz	> 50 kHz to 100 kHz	0.3 mV + 1.1 · 10 ⁻³ · U	
		> 100 kHz to 300 kHz	to 300 kHz	> 100 kHz to 300 kHz	1.5 mV + 3.8 · 10 ⁻³ · U	
	> 300 kHz to 1 MHz	> 300 kHz to 1 MHz	to 1 MHz	> 300 kHz to 1 MHz	1.5 mV + 15 · 10 ⁻³ · U	
		> 12 V to 120 V	10 Hz to 40 Hz	> 12 V to 120 V	6 mV + 0.25 · 10 ⁻³ · U	
		> 40 Hz to 1 kHz	to 1 kHz	> 40 Hz to 1 kHz	3 mV + 0.25 · 10 ⁻³ · U	
DC current Measuring instruments	10 µA to < 330 µA 0.33 mA to < 3.3 mA 3.3 mA to < 33 mA 33 mA to < 330 mA 0.33 A to < 1.1 A 1.1 A to < 3 A 3 A to < 11 A 11 A to < 20.5 A	10 Hz to 40 Hz > 40 Hz to 1 kHz > 1 kHz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz	10 Hz to 40 Hz > 40 Hz to 1 kHz > 1 kHz to 20 kHz > 20 kHz to 50 kHz	10 Hz to 40 Hz > 40 Hz to 1 kHz > 1 kHz to 20 kHz > 20 kHz to 50 kHz	0.6 mV + 90 · 10 ⁻⁶ · U 0.3 mV + 88 · 10 ⁻⁶ · U 0.3 mV + 0.17 · 10 ⁻³ · U 0.3 mV + 0.36 · 10 ⁻³ · U 0.3 mV + 1.1 · 10 ⁻³ · U 1.5 mV + 3.8 · 10 ⁻³ · U 1.5 mV + 15 · 10 ⁻³ · U	<i>I</i> = measured value
DC current Sources	10 µA to 120 µA > 0.12 mA to 1.2 mA > 1.2 mA to 12 mA > 12 mA to 120 mA > 0.12 A to 1.05 A	10 µA to 120 µA > 0.12 mA to 1.2 mA > 1.2 mA to 12 mA > 12 mA to 120 mA > 0.12 A to 1.05 A	10 µA to 120 µA > 0.12 mA to 1.2 mA > 1.2 mA to 12 mA > 12 mA to 120 mA > 0.12 A to 1.05 A	10 µA to 120 µA > 0.12 mA to 1.2 mA > 1.2 mA to 12 mA > 12 mA to 120 mA > 0.12 A to 1.05 A	1 nA + 24 · 10 ⁻⁶ · I 6 nA + 24 · 10 ⁻⁶ · I 60 nA + 24 · 10 ⁻⁶ · I 0.6 µA + 42 · 10 ⁻⁶ · I 60 µA + 0.12 · 10 ⁻³ · I	with 10 mΩ Shunt
DC current Current clamps	0.1 A to < 20 A 20 A to < 150 A 150 A to 1000 A	0.1 A to < 20 A 20 A to < 150 A 150 A to 1000 A	0.1 A to < 20 A 20 A to < 150 A 150 A to 1000 A	0.1 A to < 20 A 20 A to < 150 A 150 A to 1000 A	0.2 A + 2 · 10 ⁻³ · I 0.2 A + 5 · 10 ⁻³ · I 0.5 A + 5 · 10 ⁻³ · I	with 50 turn coil
AC current Measuring instruments	30 µA to < 330 µA	10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz	10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz	0.3 µA + 2.4 · 10 ⁻³ · I 0.3 µA + 1.8 · 10 ⁻³ · I 0.3 µA + 1.5 · 10 ⁻³ · I 0.3 µA + 3.6 · 10 ⁻³ · I 0.4 µA + 9.5 · 10 ⁻³ · I		
	0.33 mA to < 3.3 mA	10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz	10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz	0.3 µA + 2.4 · 10 ⁻³ · I 0.3 µA + 1.5 · 10 ⁻³ · I 0.3 µA + 1.2 · 10 ⁻³ · I 0.4 µA + 2.5 · 10 ⁻³ · I 0.5 µA + 6.1 · 10 ⁻³ · I		

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Measurement quantity / Calibration item	Range	Measurement conditions / procedure		Expanded uncertainty of measurement ¹	Remarks
AC current Measuring instruments	3.3 mA to < 33 mA	10 Hz to 20 Hz	> 20 Hz to 45 Hz	2.5 $\mu\text{A} + 2.1 \cdot 10^{-3} \cdot I$	$I = \text{measured value}$
		> 45 Hz to 1 kHz	> 1 kHz to 5 kHz	2.5 $\mu\text{A} + 1.2 \cdot 10^{-3} \cdot I$	
		> 5 kHz to 10 kHz		2.5 $\mu\text{A} + 0.5 \cdot 10^{-3} \cdot I$	
	33 mA to < 330 mA	10 Hz to 20 Hz	> 20 Hz to 45 Hz	2.5 $\mu\text{A} + 1.1 \cdot 10^{-3} \cdot I$	
		> 45 Hz to 1 kHz	> 1 kHz to 5 kHz	3.8 $\mu\text{A} + 2.6 \cdot 10^{-3} \cdot I$	
	0.33 A to < 1.1 A	10 Hz to 45 Hz	> 45 Hz to 1 kHz	0.13 mA + 2.2 · 10 ⁻³ · I	
		> 1 kHz to 5 kHz	> 5 kHz to 10 kHz	0.13 mA + 0.6 · 10 ⁻³ · I	
				1.2 mA + 7 · 10 ⁻³ · I	
				5.9 mA + 30 · 10 ⁻³ · I	
	1.1 A to < 3 A	10 Hz to 45 Hz	> 45 Hz to 1 kHz	0.13 mA + 2.2 · 10 ⁻³ · I	
		> 1 kHz to 5 kHz	> 5 kHz to 10 kHz	0.13 mA + 0.7 · 10 ⁻³ · I	
	3 A to < 11 A	45 Hz to 100 Hz	> 100 Hz to 1 kHz	2.4 mA + 0.73 · 10 ⁻³ · I	
		> 1 kHz to 5 kHz		2.4 mA + 1.3 · 10 ⁻³ · I	
				2.4 mA + 35 · 10 ⁻³ · I	
	11 A to < 20.5 A	45 Hz to 100 Hz	> 100 Hz to 1 kHz	6 mA + 1.6 · 10 ⁻³ · I	
		> 1 kHz to 5 kHz		6 mA + 1.8 · 10 ⁻³ · I	
				6 mA + 35 · 10 ⁻³ · I	
	10 μA to 120 μA	10 Hz to 20 Hz	> 20 Hz to 45 Hz	50 nA + 4.9 · 10 ⁻³ · I	
AC current Sources		> 45 Hz to 1 kHz		50 nA + 4.9 · 10 ⁻³ · I	
	> 0.12 mA to 1.2 mA	10 Hz to 20 Hz	> 20 Hz to 45 Hz	0.3 $\mu\text{A} + 4.8 \cdot 10^{-3} \cdot I$	
		> 45 Hz to 100 Hz	> 100 Hz to 5 kHz	0.3 $\mu\text{A} + 1.9 \cdot 10^{-3} \cdot I$	
				0.3 $\mu\text{A} + 0.72 \cdot 10^{-3} \cdot I$	
	> 1.2 mA to 12 mA	10 Hz to 20 Hz	> 20 Hz to 45 Hz	2.6 $\mu\text{A} + 4.7 \cdot 10^{-3} \cdot I$	
		> 45 Hz to 100 Hz	> 100 Hz to 5 kHz	2.6 $\mu\text{A} + 0.71 \cdot 10^{-3} \cdot I$	
	> 12 mA to 120 mA	10 Hz to 20 Hz	> 20 Hz to 45 Hz	25 $\mu\text{A} + 4.7 \cdot 10^{-3} \cdot I$	
		> 45 Hz to 100 Hz	> 100 Hz to 5 kHz	25 $\mu\text{A} + 1.8 \cdot 10^{-3} \cdot I$	
				25 $\mu\text{A} + 0.71 \cdot 10^{-3} \cdot I$	
				25 $\mu\text{A} + 0.4 \cdot 10^{-3} \cdot I$	
	> 0.12 A to 1.05 A	10 Hz to 20 Hz	> 20 Hz to 45 Hz	0.25 mA + 4.7 · 10 ⁻³ · I	
		> 45 Hz to 100 Hz	> 100 Hz to 5 kHz	0.25 mA + 1.9 · 10 ⁻³ · I	
	> 1.05 A to 20 A	10 Hz to 1 kHz		0.25 mA + 1.0 · 10 ⁻³ · I	with 10 m Ω Shunt
				0.25 mA + 1.3 · 10 ⁻³ · I	

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Calibration and Measurement Capabilities (CMC)						
Measurement quantity / Calibration item	Range		Measurement conditions / procedure		Expanded uncertainty of measurement ¹	Remarks
AC current Current clamps	0.1 A to < 20 A		45 Hz to 1 kHz		8 mA + 3 · 10 ⁻³ · I	I = measured value
	20 A to < 150 A		45 Hz to 440 Hz		50 mA + 9 · 10 ⁻³ · I	with 50 turn coil
DC resistance Measuring instruments	150 A to < 1000 A				0.12 A + 9 · 10 ⁻³ · I	
	0.01 Ω to < 11 Ω				2 mΩ + 50 · 10 ⁻⁶ · R	R = measured value
	11 Ω to < 33 Ω				2 mΩ + 45 · 10 ⁻⁶ · R	
	33 Ω to < 1.1 kΩ				2 mΩ + 40 · 10 ⁻⁶ · R	
	1.1 kΩ to < 11 kΩ				22 mΩ + 40 · 10 ⁻⁶ · R	
	11 kΩ to < 110 kΩ				0.22 Ω + 40 · 10 ⁻⁶ · R	
	110 kΩ to < 1.1 MΩ				2.2 Ω + 45 · 10 ⁻⁶ · R	
	1.1 MΩ to < 3.3 MΩ				32 Ω + 70 · 10 ⁻⁶ · R	
	3.3 MΩ to < 11 MΩ				60 Ω + 0.14 · 10 ⁻³ · R	
	11 MΩ to < 33 MΩ				2.5 kΩ + 0.27 · 10 ⁻³ · R	
	33 MΩ to < 110 MΩ				3.1 kΩ + 0.52 · 10 ⁻³ · R	
DC resistance Sources	110 MΩ to < 330 MΩ				0.12 MΩ + 5 · 10 ⁻³ · R	R = measured value
	330 MΩ to < 1.1 GΩ				0.12 MΩ + 20 · 10 ⁻³ · R	
DC power Measuring instruments	0.01 Ω to 12 Ω				0.1 mΩ + 18 · 10 ⁻⁶ · R	P = measured value
	> 12 Ω to 120 Ω				0.7 mΩ + 15 · 10 ⁻⁶ · R	
	> 120 Ω to 1.2 kΩ				0.7 mΩ + 13 · 10 ⁻⁶ · R	
	> 1.2 kΩ to 12 kΩ				7 mΩ + 13 · 10 ⁻⁶ · R	
	> 12 kΩ to 120 kΩ				70 mΩ + 13 · 10 ⁻⁶ · R	
	> 120 kΩ to 1.2 MΩ				2.2 Ω + 18 · 10 ⁻⁶ · R	
	> 1.2 MΩ to 12 MΩ				0.12 kΩ + 55 · 10 ⁻⁶ · R	
	> 12 MΩ to 120 MΩ				1.2 kΩ + 0.55 · 10 ⁻³ · R	
	> 120 MΩ to 1.2 GΩ				12 kΩ + 5.5 · 10 ⁻³ · R	
	0,1 W to < 336 W		3,3 mA to < 0,33 A		0,3 · 10 ⁻³ · P	
AC power Measuring instruments	1 W to < 3059 W		0,33 A to < 3 A		0,4 · 10 ⁻³ · P	P = measured value
	10 W to 20,9 kW		3 A to 20,5 A		0,9 · 10 ⁻³ · P	
	0,1 W to < 20,9 kW		3,3 mA to < 20,5 A		4 · 10 ⁻³ · P	
	10 W to < 153 kW		20,5 A to < 150 A		6 · 10 ⁻³ · P	
	100 W to 1 MW		150 A to 1 kA		8 · 10 ⁻³ · P	
	1 W to 91,8 W		33 mA to < 90 mA		1,5 · 10 ⁻³ · P	
AC power Measuring instruments	1 W to 336 W		90 mA to < 0,33 A		1,0 · 10 ⁻³ · P	Frequencies from 45 Hz to 65 Hz $\cos \varphi = 1$ single-phase
	1 W to 917 W		0,33 A to < 0,9 A		1,4 · 10 ⁻³ · P	
	1 W to 2243 W		0,9 A to < 2,2 A		1,2 · 10 ⁻³ · P	
	10 W to 4590 W		2,2 A to < 4,5 A		1,4 · 10 ⁻³ · P	
	10 W to 20,9 kW		4,5 A to < 20,5 A		1,3 · 10 ⁻³ · P	
	1 W to < 20,9 kW		33 mA to < 20,5 A		6 · 10 ⁻³ · P	
	10 W to < 153 kW		20,5 A to < 150 A		10 · 10 ⁻³ · P	
	100 W to 1 MW		150 A to 1 kA		12 · 10 ⁻³ · P	

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Resistance Measuring instruments	10 kΩ	to < 40 kΩ	U < 65 V	2,5 · 10 ⁻³ · R	R = measured value U = test voltage High impedance resistance e.g. Insulation tester for electrical safety
	40 kΩ	to < 100 kΩ	U < 400 V	2,5 · 10 ⁻³ · R	
	100 kΩ	to < 200 kΩ	U < 800 V	2,5 · 10 ⁻³ · R	
	200 kΩ	to < 1 MΩ	U < 1100 V	2,5 · 10 ⁻³ · R	
	1 MΩ	to < 2 MΩ	U < 1575 V	3,6 · 10 ⁻³ · R	
	2 MΩ	to < 10 MΩ	U < 2500 V	3,6 · 10 ⁻³ · R	
	10 MΩ	to < 1 GΩ	U < 3000 V	6,0 · 10 ⁻³ · R	
	10 MΩ	to < 1 GΩ	U < 5500 V	7,0 · 10 ⁻³ · R	
	1 GΩ	to < 10 GΩ	U < 3000 V	13 · 10 ⁻³ · R	
	1 GΩ	to < 10 GΩ	U < 5500 V	17 · 10 ⁻³ · R	
Resistance Measuring instruments	10 GΩ	to 100 GΩ	U < 5500 V	40 · 10 ⁻³ · R	
	100 mΩ	to < 5 Ω		10 mΩ + 2,3 · 10 ⁻³ · R	Low impedance resistance e.g. PE resistance tester for electrical safety
	5 Ω	to < 30 Ω		10 mΩ + 1,7 · 10 ⁻³ · R	
	30 Ω	to < 200 Ω		10 mΩ + 1,7 · 10 ⁻³ · R	
	200 Ω	to < 500 Ω		1,8 · 10 ⁻³ · R	
Resistance Measuring instruments	500 Ω	to < 10 kΩ		1,7 · 10 ⁻³ · R	
	14 mΩ			0,4 mΩ	Earth resistance Line impedance Loop impedance e.g. PE resistance tester or ground resistance tester for electrical safety
	39 mΩ			0,6 mΩ	
	94 mΩ			1 mΩ	
	340 mΩ			1,6 mΩ	
	490 mΩ			2,1 mΩ	
	960 mΩ			3,8 mΩ	
	1,7 Ω			6,6 mΩ	
	4,7 Ω			20 mΩ	
	9 Ω			35 mΩ	
	17 Ω			35 mΩ	
	47 Ω			250 mΩ	
	90 Ω			400 mΩ	
	170 Ω			800 mΩ	
	470 Ω			2 Ω	
Leakage current Measuring instruments	900 Ω			4 Ω	
	1,7 kΩ			8 Ω	
	0,1 mA	to < 0,3 mA		3 μA + 2 · 10 ⁻³ · I	I = measured value e.g. leakage current tester for electrical safety
RCD initiation time Measuring instruments	0,3 mA	to < 3 mA		4 μA + 3 · 10 ⁻³ · I	
	3 mA	to 30 mA		30 μA + 3 · 10 ⁻³ · I	
	10 mA	to 3 A		12 · 10 ⁻³ · I	I = measured value
RCD initiation time Measuring instruments	10 ms	to 5 s		0,25 ms + 0,2 · 10 ⁻³ · t	t = measured value

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Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Oscilloscope quantities Vertical deflection	5 mV _{pp} to < 0,5 V _{pp} 0,5 V _{pp} to 6,6 V _{pp}	DC, 10 Hz to 1 kHz	40 µV + 2,2 · 10 ⁻³ · U 2,2 · 10 ⁻³ · U	$R_i = 50 \Omega$
	5 mV _{pp} to < 0,5 V _{pp} 0,5 V _{pp} to 6,6 V _{pp}	> 1 kHz to 10 kHz	40 µV + 2,5 · 10 ⁻³ · U 2,5 · 10 ⁻³ · U	
	5 mV _{pp} to < 0,5 V _{pp} 0,5 V _{pp} to 130 V _{pp}	DC, 10 Hz to 1 kHz	40 µV + 1,5 · 10 ⁻³ · U 1,5 · 10 ⁻³ · U	$R_i = 1 M\Omega$
	5 mV _{pp} to < 0,5 V _{pp} 0,5 V _{pp} to 130 V _{pp}	> 1 kHz to 10 kHz	40 µV + 2,5 · 10 ⁻³ · U 2,5 · 10 ⁻³ · U	
Horizontal deflection	1 ns to 20 ms > 50 ms to 5 s		$2,5 \cdot 10^{-6} \cdot t$ $(25 \cdot 10^{-6} + 1 \cdot 10^{-3} \cdot \frac{t_s}{s}) \cdot t$	$R_i = 50 \Omega$ t = time in s t_s = triggered time in s
Bandwidth	5 mV to 5,5 V	50 kHz to 100 MHz > 100 MHz to 300 MHz > 300 MHz to 600 MHz	30 · 10 ⁻³ · f 35 · 10 ⁻³ · f 45 · 10 ⁻³ · f	$R_i = 50 \Omega$
Rise time	0,5 ns to 10 ms	5 mV to 2,5 V at 1 kHz to 10 MHz	$50 \cdot 10^{-3} \cdot t_r$	t_r = Rise time
Input resistance	40 Ω to 60 Ω		$2 \cdot 10^{-3} \cdot R$	R = measured value 50 Ω nominal input resistance
	500 kΩ to 1,5 MΩ		$2 \cdot 10^{-3} \cdot R$	R = measured value 1 MΩ nominal input resistance
Time and frequency				
Frequency	1 Hz to 2,2 GHz		$2 \cdot 10^{-10} \cdot f + U_{Tf}$	f, t = measured value
Time interval	1 µs to 10 s		$2 \cdot 10^{-10} \cdot t + U_{Tt} + 1 \text{ ns}$	U_{Tf}, U_{Tt} = trigger uncertainty

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On-site Calibration

Calibration and Measurement Capabilities (CMC)				
Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Length				
Surface plates * Flatness deviation	to 50 µm	VDI/VDE/DGQ 2618 part 6.2:2014 to 8 m edge length	$1.1 \mu\text{m} + 2.7 \cdot 10^{-6} \cdot l$	l = measured length with inclination measuring instruments
Height gauges *	0 mm to 1000 mm	VDI/VDE/DGQ 2618 part 16.1:2009	$1.0 \mu\text{m} + 1.4 \cdot 10^{-6} \cdot l$	
Deviation from straightness and perpendicularity	to 40 µm		3 µm	
Horizontal length measuring devices *	0 mm to 5000 mm	VDI/VDE/DGQ 2618 part 17.1:2015	$0.12 \mu\text{m} + 0.07 \cdot 10^{-6} \cdot l$	with laser interferometer
	0 mm to 200 mm		$0.12 \mu\text{m} + 0.6 \cdot 10^{-6} \cdot l$	
Height calipers * with analogue display with digital display	0 mm to 600 mm	VDI/VDE/DGQ 2618 part 9.3:2006	$30 \mu\text{m} + 30 \cdot 10^{-6} \cdot l$	
			$20 \mu\text{m} + 30 \cdot 10^{-6} \cdot l$	
Coordinate measuring technology	Devices featuring a measuring plane with a face diagonal $\leq 900 \text{ mm}$	Calibration of metrological characteristics according to guideline DKD-R 4-3 part 18.1:2018, and the following standards and guidelines DIN EN ISO 10360 VDI/VDE 2617		l = measured length
			$0.8 \mu\text{m}$	
		The error of indication for size measurement E_{UX} , E_{UY} and E_{UXY} is determined with a graduated scale made of glass according to DIN EN ISO 10360-7:2011	$1.6 \mu\text{m} + 1 \cdot 10^{-6} \cdot l$	

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Calibration and Measurement Capabilities (CMC)

Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Length				
Gap gauges *	5 mm to 200 mm	VDI/VDE/DGQ 2618 part 4.7:2005	$3 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	l = measured length
Calipers for external, internal and depth dimensions *	0 mm to 300 mm	VDI/VDE/DGQ 2618 part 9.1:2006	$30 \mu\text{m} + 30 \cdot 10^{-6} \cdot l$	
	> 300 mm to 1500 mm		$50 \mu\text{m} + 30 \cdot 10^{-6} \cdot l$	
Depth calipers *	0 mm to 300 mm	VDI/VDE/DGQ 2618 part 9.2:2006	$30 \mu\text{m} + 30 \cdot 10^{-6} \cdot l$	l = measured length
	> 300 mm to 1000 mm		$50 \mu\text{m} + 30 \cdot 10^{-6} \cdot l$	
Height calipers * with analogue display	0 mm to 600 mm	VDI/VDE/DGQ 2618 part 9.3:2006	$30 \mu\text{m} + 30 \cdot 10^{-6} \cdot l$	
with digital display			$20 \mu\text{m} + 30 \cdot 10^{-6} \cdot l$	
Micrometers *	0 mm to 100 mm	VDI/VDE/DGQ 2618 part 10.1:2001	$3 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	l = final value of the measuring range
	> 100 mm to 500 mm		$4 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	
	> 500 mm to 1000 mm		$5 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	
Micrometers according to DIN 863-3 form D10	0 mm to 100 mm	TK 2:2021-02	$5 \mu\text{m} + 10 \cdot 10^{-6} \cdot d$	d = measured diameter
Reference gauges for micrometers *	25 mm to 1000 mm	VDI/VDE/DGQ 2618 part 4.4:2009	$2 \mu\text{m} + 20 \cdot 10^{-6} \cdot l$	l = measured length
Internal micrometers with three-point contact *	3 mm to 200 mm	VDI/VDE/DGQ 2618 part 10.8:2002	$4 \mu\text{m} + 10 \cdot 10^{-6} \cdot d$	d = measured diameter
Internal measuring instruments	3 mm to 200 mm	TK 57:2021-02	$2 \mu\text{m} + 10 \cdot 10^{-6} \cdot d$	
Dial gauges * Scale interval > 1 μm	to 100 mm	VDI/VDE/DGQ/DKD 2618 part 11.1:2021	$3.2 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	l = measured length
Scale interval $\leq 1 \mu\text{m}$			$2.8 \mu\text{m} + 11 \cdot 10^{-6} \cdot l$	
Dial indicators *	to 3 mm	VDI/VDE/DGQ 2618 part 11.2:2002	1.9 μm	
Lever gauges *	to 1.6 mm	VDI/VDE/DGQ 2618 part 11.3:2002	2 μm	
Dial gauges * with digital display	to 100 mm	VDI/VDE/DGQ/DKD 2618 part 11.4:2020	$3 \mu\text{m} + 10 \cdot 10^{-6} \cdot l$	
Thickness gauges * Scale interval 1 μm	0 mm to 30 mm	VDI/VDE/DGQ 2618 part 12.1:2005	$1.1 \mu\text{m} + 8 \cdot 10^{-6} \cdot l$	
Scale interval 10 μm			6 μm	
Feeler gauges	10 μm to 2 mm	TK 19:2021-02	1.7 μm	

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Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks	
Lever gauges (quicktests) for external measurements *	0 mm to 100 mm	VDI/VDE/DGQ 2618 part 12.1:2005	6 µm		
Lever gauges (quicktests) for internal measurements *	2.5 mm to 500 mm	VDI/VDE/DGQ 2618 part 13.1:2005	6 µm		
Internal micrometers with two-point contact *	25 mm to 100 mm	VDI/VDE/DGQ 2618 part 10.7:2010	3 µm + 10 · 10 ⁻⁶ · l		
	> 100 mm to 500 mm		4 µm + 10 · 10 ⁻⁶ · l		
	> 500 mm to 1000 mm		5 µm + 10 · 10 ⁻⁶ · l		
Extensions for internal micrometers with two-point contact *	25 mm to 1000 mm	VDI/VDE/DGQ 2618 part 10.7:2010	2 µm + 20 · 10 ⁻⁶ · l		
Micrometers with interchangeable inserts *	0 mm to 100 mm	VDI/VDE/DGQ 2618 part 10.2:2010	3 µm + 10 · 10 ⁻⁶ · l		
	> 100 mm to 300 mm		5 µm + 10 · 10 ⁻⁶ · l		
Micrometers with dial indicators *	0 mm to 100 mm	VDI/VDE/DGQ 2618 part 10.3:2002	3 µm + 10 · 10 ⁻⁶ · l	l = measured length	
Micrometers heads *	0 mm to 50 mm	VDI/VDE/DGQ 2618 part 10.4:2008	3 µm + 10 · 10 ⁻⁶ · l		
Depth micrometers *	0 mm to 100 mm	VDI/VDE/DGQ 2618 part 10.5:2010	3 µm + 10 · 10 ⁻⁶ · l		
	> 100 mm to 500 mm		4 µm + 10 · 10 ⁻⁶ · l		
Bore gauges with two-point contact * Form I – III	1 mm to 800 mm	VDI/VDE/DGQ 2618 part 13.2:2005	2.3 µm	Measuring length up to 3 mm	
Protractors * Flatness deviation	0° to 360°	VDI/VDE/DGQ 2618 part 7.2:2008	5 µm		
Parallelism deviation			5 µm		
Angle * Scale interval 5'	0° to 360°		4'		
Scale interval 1°			24'		
Setting plug gauges * Diameter	1 mm to 500 mm	VDI/VDE/DGQ 2618 part 4.1:2006, option 3, option 4	0.8 µm + 3 · 10 ⁻⁶ · d	d = measured diameter	
Setting ring gauges * Diameter	2 mm to 200 mm	VDI/VDE/DGQ 2618 part 4.1:2006 option 3, option 4	0.8 µm + 3 · 10 ⁻⁶ · d		
Measuring pins / Pins for screw threads * Diameterr	0.17 mm to 50 mm	VDI/VDE/DGQ 2618 part 4.2:2007, option 1	0.8 µm		
Electrical probe and measuring device *	0 mm to 10 mm	VDI/VDE/DGQ 2618 part 14.1:2010	2 µm		
Layer thickness gauges	20 mm	TK 91:2021-02	0.7 µm + 180 · 10 ⁻⁶ · l	l = measured length	

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Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Thread gauges * single-start cylindrical external and internal threads with straight flanks, symmetrical profile and nominal thread angle 55° to 60°				
External thread with nominal lead 0.25 mm to 5.5 mm Simple pitch diameter	Nominal diameter:	VDI/VDE/DGQ 2618 part 4.8:2006 (option 1) Three wire procedure (vertical to thread axis)	2.8 μm + 10 · 10 ⁻⁶ · d	d = pitch diameter
	2 mm to 200 mm			
Internal thread with nominal lead 0.7 mm to 6.0 mm Simple pitch diameter	Nominal diameter:	VDI/VDE/DGQ 2618 part 4.9:2006 (option 1) Two ball procedure (vertical to thread axis)	2.8 μm + 10 · 10 ⁻⁶ · d	
	4 mm to 200 mm			
DC and low frequency quantities				
DC voltage Measuring instruments	1 mV to < 330 mV		2.0 μV + 35 · 10 ⁻⁶ · U	U = measured value
	0.33 V to < 3.3 V		3.0 μV + 16 · 10 ⁻⁶ · U	
	3.3 V to < 33 V		24 μV + 18 · 10 ⁻⁶ · U	
	33 V to < 330 V		0.2 mV + 24 · 10 ⁻⁶ · U	
	330 V to < 1000 V		1.7 mV + 24 · 10 ⁻⁶ · U	
DC voltage Sources	10 mV to 120 mV		2.0 μV + 12 · 10 ⁻⁶ · U	
	> 0.12 V to 1.2 V		2.0 μV + 10 · 10 ⁻⁶ · U	
	> 1.2 V to 12 V		2.5 μV + 10 · 10 ⁻⁶ · U	
	> 12 V to 120 V		35 μV + 14 · 10 ⁻⁶ · U	
	> 120 V to 1050 V		0.1 mV + 22 · 10 ⁻⁶ · U	
AC voltage Measuring instruments	1 mV to < 33 mV	10 Hz to 45 Hz > 45 Hz to 10 kHz > 10 kHz to 20 kHz > 20 kHz to 50 kHz > 50 kHz to 100 kHz > 100 kHz to 500 kHz	8 μV + 1.0 · 10 ⁻³ · U 8 μV + 0.2 · 10 ⁻³ · U 8 μV + 0.25 · 10 ⁻³ · U 8 μV + 1.3 · 10 ⁻³ · U 15 μV + 4.2 · 10 ⁻³ · U 60 μV + 10 · 10 ⁻³ · U	U = measured value
	33 mV to < 330 mV		10 μV + 0.4 · 10 ⁻³ · U 10 μV + 0.2 · 10 ⁻³ · U 10 μV + 0.2 · 10 ⁻³ · U 10 μV + 0.43 · 10 ⁻³ · U 40 μV + 0.95 · 10 ⁻³ · U 85 μV + 2.5 · 10 ⁻³ · U	
	0.33 V to < 3.3 V		60 μV + 0.4 · 10 ⁻³ · U 75 μV + 0.2 · 10 ⁻³ · U 75 μV + 0.24 · 10 ⁻³ · U 60 μV + 0.35 · 10 ⁻³ · U 0.15 mV + 0.85 · 10 ⁻³ · U 0.7 mV + 3 · 10 ⁻³ · U	

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Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
AC voltage Measuring instruments	3.3 V to < 33 V	10 Hz to 45 Hz	0.75 mV + 0.38 · 10 ⁻³ · U	$U = \text{measured value}$
		> 45 Hz to 10 kHz	0.7 mV + 0.2 · 10 ⁻³ · U	
		> 10 kHz to 20 kHz	0.7 mV + 0.29 · 10 ⁻³ · U	
		> 20 kHz to 50 kHz	0.7 mV + 0.42 · 10 ⁻³ · U	
		> 50 kHz to 100 kHz	1.9 mV + 1.1 · 10 ⁻³ · U	
	33 V to < 330 V	10 Hz to 45 Hz	2.4 mV + 0.24 · 10 ⁻³ · U	
		> 45 Hz to 10 kHz	7 mV + 0.25 · 10 ⁻³ · U	
		> 10 kHz to 20 kHz	7 mV + 0.31 · 10 ⁻³ · U	
		> 20 kHz to 50 kHz	7 mV + 0.37 · 10 ⁻³ · U	
		> 50 kHz to 100 kHz	58 mV + 2.4 · 10 ⁻³ · U	
AC voltage Sources	10 mV to 120 mV	45 Hz to 1 kHz	13 mV + 0.35 · 10 ⁻³ · U	$U = \text{measured value}$
		> 1 kHz to 5 kHz	13 mV + 0.30 · 10 ⁻³ · U	
		> 5 kHz to 10 kHz	13 mV + 0.35 · 10 ⁻³ · U	
		10 Hz to 40 Hz	25 µV + 0.11 · 10 ⁻³ · U	
		> 40 Hz to 1 kHz	20 µV + 0.11 · 10 ⁻³ · U	
		> 1 kHz to 20 kHz	20 µV + 0.19 · 10 ⁻³ · U	
	> 0.12 V to 1,2 V	> 20 kHz to 50 kHz	20 µV + 0.38 · 10 ⁻³ · U	
		> 50 kHz to 100 kHz	20 µV + 1 · 10 ⁻³ · U	
		> 100 kHz to 300 kHz	20 µV + 4.2 · 10 ⁻³ · U	
		10 Hz to 40 Hz	60 µV + 0.10 · 10 ⁻³ · U	
		> 40 Hz to 1 kHz	40 µV + 0.10 · 10 ⁻³ · U	
		> 1 kHz to 20 kHz	40 µV + 0.18 · 10 ⁻³ · U	
		> 20 kHz to 50 kHz	40 µV + 0.37 · 10 ⁻³ · U	
	> 1.2 V to 12 V	> 50 kHz to 100 kHz	40 µV + 1.15 · 10 ⁻³ · U	
		> 100 kHz to 300 kHz	0.15 mV + 4 · 10 ⁻³ · U	
		> 300 kHz to 1 MHz	0.15 mV + 17 · 10 ⁻³ · U	
		10 Hz to 40 Hz	0.6 mV + 90 · 10 ⁻⁶ · U	
		> 40 Hz to 1 kHz	0.3 mV + 88 · 10 ⁻⁶ · U	
		> 1 kHz to 20 kHz	0.3 mV + 0.17 · 10 ⁻³ · U	
		> 20 kHz to 50 kHz	0.3 mV + 0.36 · 10 ⁻³ · U	
	> 12 V to 120 V	> 50 kHz to 100 kHz	0.3 mV + 1.1 · 10 ⁻³ · U	
		> 100 kHz to 300 kHz	1.5 mV + 3.8 · 10 ⁻³ · U	
		> 300 kHz to 1 MHz	1.5 mV + 15 · 10 ⁻³ · U	
		10 Hz to 40 Hz	6 mV + 0.25 · 10 ⁻³ · U	
		> 40 Hz to 1 kHz	3 mV + 0.25 · 10 ⁻³ · U	
	> 120 V to 700 V	> 1 kHz to 20 kHz	3 mV + 0.25 · 10 ⁻³ · U	
		> 20 kHz to 50 kHz	3 mV + 0.45 · 10 ⁻³ · U	
		> 50 kHz to 100 kHz	3 mV + 1.6 · 10 ⁻³ · U	
		10 Hz to 40 Hz	60 mV + 0.5 · 10 ⁻³ · U	
		> 40 Hz to 1 kHz	30 mV + 0.5 · 10 ⁻³ · U	
		> 1 kHz to 20 kHz	30 mV + 0.75 · 10 ⁻³ · U	
		> 20 kHz to 50 kHz	30 mV + 1.6 · 10 ⁻³ · U	

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Calibration and Measurement Capabilities (CMC)

Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
DC current Measuring instruments	10 µA to < 330 µA 0.33 mA to < 3.3 mA 3.3 mA to < 33 mA 33 mA to < 330 mA 0.33 A to < 1.1 A 1.1 A to < 3 A 3 A to < 11 A 11 A to < 20.5 A		0.1 µA + 0.22 · 10 ⁻³ · I 0.1 µA + 0.15 · 10 ⁻³ · I 0.3 µA + 0.15 · 10 ⁻³ · I 3 µA + 0.15 · 10 ⁻³ · I 50 µA + 0.24 · 10 ⁻³ · I 50 µA + 0.45 · 10 ⁻³ · I 0.6 mA + 0.60 · 10 ⁻³ · I 1.8 mA + 1.3 · 10 ⁻³ · I	I = measured value
DC current Sources	10 µA to 120 µA > 0.12 mA to 1.2 mA > 1.2 mA to 12 mA > 12 mA to 120 mA > 0.12 A to 1.05 A		1 nA + 24 · 10 ⁻⁶ · I 6 nA + 24 · 10 ⁻⁶ · I 60 nA + 24 · 10 ⁻⁶ · I 0.6 µA + 42 · 10 ⁻⁶ · I 60 µA + 0.12 · 10 ⁻³ · I	
	> 1.05 A to 20 A		0.3 mA + 18 · 10 ⁻⁶ · I	with 10 mΩ Shunt
DC current Current clamps	0.1 A to < 20 A 20 A to < 150 A 150 A to 1000 A		2 mA + 2 · 10 ⁻³ · I 0.2 A + 5 · 10 ⁻³ · I 0.5 A + 5 · 10 ⁻³ · I	with 50 turn coil
AC current Measuring instruments	30 µA to < 330 µA 0.33 mA to < 3.3 mA 3.3 mA to < 33 mA 33 mA to < 330 mA 0.33 A to < 1.1 A 1.1 A to < 3 A	10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz 10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz 10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz 10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz 10 Hz to 45 Hz > 45 Hz to 1 kHz > 1 kHz to 5 kHz > 5 kHz to 10 kHz	0.3 µA + 2.4 · 10 ⁻³ · I 0.3 µA + 1.8 · 10 ⁻³ · I 0.3 µA + 1.5 · 10 ⁻³ · I 0.3 µA + 3.6 · 10 ⁻³ · I 0.4 µA + 9.5 · 10 ⁻³ · I 0.3 µA + 2.4 · 10 ⁻³ · I 0.3 µA + 1.5 · 10 ⁻³ · I 0.3 µA + 1.2 · 10 ⁻³ · I 0.4 µA + 2.5 · 10 ⁻³ · I 0.5 µA + 6.1 · 10 ⁻³ · I 2.5 µA + 2.1 · 10 ⁻³ · I 2.5 µA + 1.2 · 10 ⁻³ · I 2.5 µA + 0.5 · 10 ⁻³ · I 2.5 µA + 1.1 · 10 ⁻³ · I 3.8 µA + 2.6 · 10 ⁻³ · I 25 µA + 2.1 · 10 ⁻³ · I 25 µA + 1.2 · 10 ⁻³ · I 25 µA + 0.5 · 10 ⁻³ · I 60 µA + 1.3 · 10 ⁻³ · I 0.13 mA + 2.8 · 10 ⁻³ · I 0.13 mA + 2.2 · 10 ⁻³ · I 0.13 mA + 0.6 · 10 ⁻³ · I 1.2 mA + 7 · 10 ⁻³ · I 5.9 mA + 30 · 10 ⁻³ · I 0.13 mA + 2.2 · 10 ⁻³ · I 0.13 mA + 0.7 · 10 ⁻³ · I 1.2 mA + 7 · 10 ⁻³ · I 5.9 mA + 30 · 10 ⁻³ · I	

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Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
AC current Measuring instruments	3 A to < 11 A	45 Hz to 100 Hz > 100 Hz to 1 kHz > 1 kHz to 5 kHz	2.4 mA + 0.73 · 10 ⁻³ · I 2.4 mA + 1.3 · 10 ⁻³ · I 2.4 mA + 35 · 10 ⁻³ · I	I = measured value
	11 A to < 20.5 A	45 Hz to 100 Hz > 100 Hz to 1 kHz > 1 kHz to 5 kHz	6 mA + 1.6 · 10 ⁻³ · I 6 mA + 1.8 · 10 ⁻³ · I 6 mA + 35 · 10 ⁻³ · I	
AC current Sources	10 µA to 120 µA	10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 1 kHz	50 nA + 4.9 · 10 ⁻³ · I 50 nA + 4.9 · 10 ⁻³ · I 50 nA + 4.9 · 10 ⁻³ · I	
	> 0.12 mA to 1,2 mA	10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 100 Hz > 100 Hz to 5 kHz	0.3 µA + 4.8 · 10 ⁻³ · I 0.3 µA + 1.9 · 10 ⁻³ · I 0.3 µA + 0.72 · 10 ⁻³ · I 0.3 µA + 0.41 · 10 ⁻³ · I	
	> 1.2 mA to 12 mA	10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 100 Hz > 100 Hz to 5 kHz	2.6 µA + 4.7 · 10 ⁻³ · I 2.6 µA + 1.8 · 10 ⁻³ · I 2.6 µA + 0.71 · 10 ⁻³ · I 2.5 µA + 0.4 · 10 ⁻³ · I	
	> 12 mA to 120 mA	10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 100 Hz > 100 Hz to 5 kHz	25 µA + 4.7 · 10 ⁻³ · I 25 µA + 1.8 · 10 ⁻³ · I 25 µA + 0.71 · 10 ⁻³ · I 25 µA + 0.4 · 10 ⁻³ · I	
	> 0.12 A to 1.05 A	10 Hz to 20 Hz > 20 Hz to 45 Hz > 45 Hz to 100 Hz > 100 Hz to 5 kHz	0.25 mA + 4.7 · 10 ⁻³ · I 0.25 mA + 1.9 · 10 ⁻³ · I 0.25 mA + 1.0 · 10 ⁻³ · I 0.25 mA + 1.3 · 10 ⁻³ · I	
	> 1.05 A to 20 A	10 Hz to 1 kHz	10 mA + 0.15 · 10 ⁻³ · I	with 10 mΩ Shunt
	0.1 A to < 20 A	45 Hz to 1 kHz	8 mA + 3 · 10 ⁻³ · I	
	20 A to < 150 A 150 A to < 1000 A	45 Hz to 440 Hz	50 mA + 9 · 10 ⁻³ · I 0.12 A + 9 · 10 ⁻³ · I	with 50 turn coil
DC resistance Measuring instruments	0.01 Ω to < 11 Ω 11 Ω to < 33 Ω 33 Ω to < 1.1 kΩ 1.1 kΩ to < 11 kΩ 11 kΩ to < 110 kΩ 110 kΩ to < 1.1 MΩ 1.1 MΩ to < 3.3 MΩ 3.3 MΩ to < 11 MΩ 11 MΩ to < 33 MΩ 33 MΩ to < 110 MΩ 110 MΩ to < 330 MΩ 330 MΩ to < 1.1 GΩ		2 mΩ + 50 · 10 ⁻⁶ · R 2 mΩ + 45 · 10 ⁻⁶ · R 2 mΩ + 40 · 10 ⁻⁶ · R 22 mΩ + 40 · 10 ⁻⁶ · R 0.22 Ω + 40 · 10 ⁻⁶ · R 2.2 Ω + 45 · 10 ⁻⁶ · R 32 Ω + 70 · 10 ⁻⁶ · R 60 Ω + 0,14 · 10 ⁻³ · R 2.5 kΩ + 0,27 · 10 ⁻³ · R 3.1 kΩ + 0,52 · 10 ⁻³ · R 0.12 MΩ + 5 · 10 ⁻³ · R 0.12 MΩ + 20 · 10 ⁻³ · R	R = measured value

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Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
DC resistance Sources	0,01 Ω to 12 Ω > 12 Ω to 120 Ω > 120 Ω to 1,2 kΩ > 1,2 kΩ to 12 kΩ > 12 kΩ to 120 kΩ > 120 kΩ to 1,2 MΩ > 1,2 MΩ to 12 MΩ > 12 MΩ to 120 MΩ > 120 MΩ to 1,2 GΩ		0,1 mΩ + 18 · 10 ⁻⁶ · R 0,7 mΩ + 15 · 10 ⁻⁶ · R 0,7 mΩ + 13 · 10 ⁻⁶ · R 7 mΩ + 13 · 10 ⁻⁶ · R 70 mΩ + 13 · 10 ⁻⁶ · R 2,2 Ω + 18 · 10 ⁻⁶ · R 0,12 kΩ + 55 · 10 ⁻⁶ · R 1,2 kΩ + 0,55 · 10 ⁻³ · R 12 kΩ + 5,5 · 10 ⁻³ · R	R = measured value
DC power Measuring instruments	0,1 W to < 336 W 1 W to < 3059 W 10 W to 20,9 kW	3,3 mA to < 0,33 A 0,33 A to < 3 A 3 A to 20,5 A	0,3 · 10 ⁻³ · P 0,4 · 10 ⁻³ · P 0,9 · 10 ⁻³ · P	P = measured value
	0,1 W to < 20,9 kW 10 W to < 153 kW 100 W to 1 MW	3,3 mA to < 20,5 A 20,5 A to < 150 A 150 A to 1 kA	4 · 10 ⁻³ · P 6 · 10 ⁻³ · P 8 · 10 ⁻³ · P	
AC power Measuring instruments	1 W to 91,8 W 1 W to 336 W 1 W to 917 W 1 W to 2243 W 10 W to 4590 W 10 W to 20,9 kW	33 mA to < 90 mA 90 mA to < 0,33 A 0,33 A to < 0,9 A 0,9 A to < 2,2 A 2,2 A to < 4,5 A 4,5 A to < 20,5 A	1,5 · 10 ⁻³ · P 1,0 · 10 ⁻³ · P 1,4 · 10 ⁻³ · P 1,2 · 10 ⁻³ · P 1,4 · 10 ⁻³ · P 1,3 · 10 ⁻³ · P	Frequencies from 45 Hz to 65 Hz $\cos \varphi = 1$ single-phase
	1 W to < 20,9 kW 10 W to < 153 kW 100 W to 1 MW	33 mA to < 20,5 A 20,5 A to < 150 A 150 A to 1 kA	6 · 10 ⁻³ · P 10 · 10 ⁻³ · P 12 · 10 ⁻³ · P	
Resistance Measuring instruments	10 kΩ to < 40 kΩ 40 kΩ to < 100 kΩ 100 kΩ to < 200 kΩ 200 kΩ to < 1 MΩ 1 MΩ to < 2 MΩ 2 MΩ to < 10 MΩ 10 MΩ to < 1 GΩ 10 MΩ to < 1 GΩ 1 GΩ to < 10 GΩ 1 GΩ to < 10 GΩ 10 GΩ to 100 GΩ	U < 65 V U < 400 V U < 800 V U < 1100 V U < 1575 V U < 2500 V U < 3000 V U < 5500 V U < 3000 V U < 5500 V U < 5500 V	2,5 · 10 ⁻³ · R 2,5 · 10 ⁻³ · R 2,5 · 10 ⁻³ · R 2,5 · 10 ⁻³ · R 3,6 · 10 ⁻³ · R 3,6 · 10 ⁻³ · R 6,0 · 10 ⁻³ · R 7,0 · 10 ⁻³ · R 13 · 10 ⁻³ · R 17 · 10 ⁻³ · R 40 · 10 ⁻³ · R	R = measured value U = test voltage High impedance resistance e.g. Insulation tester for electrical safety
Resistance Measuring instruments	100 mΩ to < 5 Ω 5 Ω to < 30 Ω 30 Ω to < 200 Ω 200 Ω to < 500 Ω 500 Ω to < 10 kΩ		10 mΩ + 2,3 · 10 ⁻³ · R 10 mΩ + 1,7 · 10 ⁻³ · R 10 mΩ + 1,7 · 10 ⁻³ · R 1,8 · 10 ⁻³ · R 1,7 · 10 ⁻³ · R	

¹ Unless otherwise specified, the unit of a variable corresponds to the unit of the measuring range.

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Calibration and Measurement Capabilities (CMC)

Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Resistance Measuring instruments	14 mΩ 39 mΩ 94 mΩ 340 mΩ 490 mΩ 960 mΩ 1,7 Ω 4,7 Ω 9 Ω 17 Ω 47 Ω 90 Ω 170 Ω 470 Ω 900 Ω 1,7 kΩ		0,4 mΩ 0,6 mΩ 1 mΩ 1,6 mΩ 2,1 mΩ 3,8 mΩ 6,6 mΩ 20 mΩ 35 mΩ 35 mΩ 250 mΩ 400 mΩ 800 mΩ 2 Ω 4 Ω 8 Ω	Earth resistance Line impedance Loop impedance e.g. PE resistance tester or ground resistance for electrical safety
Leakage current Measuring instruments	0,1 mA to < 0,3 mA 0,3 mA to < 3 mA 3 mA to 30 mA		3 μA + 2 · 10 ⁻³ · I 4 μA + 3 · 10 ⁻³ · I 30 μA + 3 · 10 ⁻³ · I	I = measured value e.g. leakage current tester for electrical safety
RCD initiation current Measuring instruments	10 mA to 3 A		12 · 10 ⁻³ · I	I = measured value
RCD initiation time t Measuring instruments	10 ms to 5 s		0,25 ms + 0,2 · 10 ⁻³ · t	t = measured value
Oscilloscope quantities	5 mV _{pp} to < 0,5 V _{pp} 0,5 V _{pp} to 6,6 V _{pp}	DC, 10 Hz to 1 kHz	40 μV + 2,2 · 10 ⁻³ · U 2,2 · 10 ⁻³ · U	$R_i = 50 \Omega$
	5 mV _{pp} to < 0,5 V _{pp} 0,5 V _{pp} to 6,6 V _{pp}	> 1 kHz to 10 kHz	40 μV + 2,5 · 10 ⁻³ · U 2,5 · 10 ⁻³ · U	
	5 mV _{pp} to < 0,5 V _{pp} 0,5 V _{pp} to 130 V _{pp}	DC, 10 Hz to 1 kHz	40 μV + 1,5 · 10 ⁻³ · U 1,5 · 10 ⁻³ · U	$R_i = 1 M\Omega$
	5 mV _{pp} to < 0,5 V _{pp} 0,5 V _{pp} to 130 V _{pp}	> 1 kHz to 10 kHz	40 μV + 2,5 · 10 ⁻³ · U 2,5 · 10 ⁻³ · U	
Horizontal deflection	1 ns to 20 ms > 50 ms to 5 s		2,5 · 10 ⁻⁶ · t (25 · 10 ⁻⁶ + 1 · 10 ⁻³ · $\frac{t_s}{s}$) · t	$R_i = 50 \Omega$ t = time in s t_s = triggered time in s
Bandwidth	5 mV to 5,5 V	50 kHz to 100 MHz > 100 MHz to 300 MHz > 300 MHz to 600 MHz	30 · 10 ⁻³ · f 35 · 10 ⁻³ · f 45 · 10 ⁻³ · f	$R_i = 50 \Omega$
Rise time	0,5 ns to 10 ms	5 mV to 2,5 V at 1 kHz to 10 MHz	50 · 10 ⁻³ · tr	tr = Rise time

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Calibration and Measurement Capabilities (CMC)				
Measurement quantity / Calibration item	Range	Measurement conditions / procedure	Expanded uncertainty of measurement ¹	Remarks
Input resistance	40 Ω to 60 Ω		2 · 10 ⁻³ · R	R = measured value 50 Ω nominal input resistance
	500 kΩ to 1,5 MΩ		2 · 10 ⁻³ · R	R = measured value 1 MΩ nominal input resistance

Abbreviations used:

CMC	Calibration and measurement capabilities (Kalibrier- und Messmöglichkeiten)
DGQ	Deutsche Gesellschaft für Qualität e.V.
DIN	Deutsches Institut für Normung e.V.
DKD	Deutscher Kalibrierdienst
DKD-R	Guideline of Deutscher Kalibrierdienst, published by Physikalisch-Technische Bundesanstalt
EURAMET	European Association of National Metrology Institutes
TK	Calibration guide of Kessler-QMP GmbH
VDE	Verband der Elektrotechnik, Elektronik und Informationstechnik e.V.
VDI	Verein Deutscher Ingenieure e.V.

β	Helix angle	f_{β}	Helix form deviation
d	Reference diameter	$f_{H\beta}$	Helix slope deviation
d_b	Base diameter	F_p	Cumulative pitch deviation
F_a	Total profile deviation	f_p	Single pitch deviation
f_{Ha}	Profile slope deviation	L_a	Profile evaluation range
f_{fa}	Profile form deviation	L_β	Helix evaluation range
F_β	Total helix deviation	m_n	Normal module

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